

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/622,467	CHOI, PIL HEON
	Examiner	Art Unit
	Quoc D. Tran	2614
		Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0228001	12-2003	Nakatsu, Makoto	379/67.1
*	B	US-2003/0059007	03-2003	Beyda, William J.	379/88.19
*	C	US-7,130,598	10-2006	Lee et al.	379/142.07
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.